

## A. Interconnect & Package 분과

2017년 2월 15일 (수), 08:30-10:00  
Room B (토파즈, 2층)

### [WB1-A] Packaging and Design

좌장: 이후정(성균관대학교)

<b>WB1-A-1</b> 08:30-08:45	<b>Mechanical Reliability of Sn-Ag-Cu and Sn-Bi BGA Solder Joints with Epoxy During Temperature-Humidity Treatments</b> Kyung-Yeol Kim <sup>1</sup> , Woo-Ram Myung <sup>2</sup> , Haksan Jeong <sup>1</sup> , and Seung-Boo Jung <sup>1</sup> <i><sup>1</sup>School of Advanced Materials Science &amp; Engineering, Sungkyunkwan University, <sup>2</sup>SKKU Advanced Institute of Nanotechnology, Sungkyunkwan University</i>
<b>WB1-A-2</b> 08:45-09:00	<b>Interposer-Level Wireless Power Transfer Scheme Design on Active Silicon Interposer in 2.5-D and 3-D IC</b> Jinwook Song, Seungtaek Jung, Shinyoung Park, Subin Kim, and Joungho Kim <i>Department of Electrical Engineering, KAIST</i>
<b>WB1-A-3</b> 09:00-09:15	<b>Signal Integrity Design of High Bandwidth Memory Interposer in 2.5D Terabyte/s Bandwidth Graphics Module</b> Hyunsuk Lee and Joungho Kim <i>School of Electrical Engineering, KAIST</i>
<b>WB1-A-4</b> 09:15-09:30	<b>New Verification Method Considering Process Variation in NAND Flash Memory</b> Young Sang Ahn, Gun Gi Song, Jin Yong Seong, Jae Won Cha, Seung Geon Yu, and Sang Hoo Hong <i>Nand Product Verification Team, Nand Tech Development Division, SK Hynix Inc.</i>
<b>WB1-A-5</b> 09:30-09:45	<b>3D Packaging System에서 저온 공정의 필요성 및 절연 박막의 특성 연구</b> 손성민, 안진호, 정덕영, 진정기, 장근호, 박병률, 이내인, 황기현, 강호규, 정은승 <i>삼성전자 반도체 연구소</i>
<b>WB1-A-6</b> 09:45-10:00	<b>Chip Guard Ring 구조 최적화 연구</b> Min-Soo Park, Jea Hyun Son, Young Geon Kwon, and Nam Seog Kim <i>SK Hynix Inc.</i>